

**Search Notes****Application/Control No.**

10/759,642

**Applicant(s)/Patent under  
Reexamination**

ERIC YEH ET AL.

**Examiner**

PIERRE-LOUIS DESIR

**Art Unit**

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	412.1	5/23/2008	PD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	5/23/2008	PD